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Substitute for form 1449/PTO				Complete If Known	
				Application Number	10/813,594-Conf. #4387
				Filing Date	March 30, 2004
				First Named Inventor	Seiji Ichiyoshi
				Art Unit	2138
				Examiner Name	J. C. Kerveros
Sheet	1	of	2	Attorney Docket Number	02008/106002

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number-Kind Code ² (if known)			
IJK/	AA*	US-2003/0005375-A1	01-02-2003	Takasugi et al.	
	AB*	US-2001/016922 A1	08-23-2001	Takasugi et al.	
	AC*	US-5,425,036	06-13-1995	Liu et al.	
	AD*	US-5,991,907	11-23-1999	Stroud et al.	
	AE*	US-6,077,304	06-20-2000	Kasuya	
	AF*	US-6,108,806	08-22-2000	Abramovici et al.	
	AG*	US-6,202,182	03-13-2001	Abramovici et al.	
↓	AH*	US-2002/0038203-A1	03-28-2002	Tsuchiya	
	AI*	US-6,631,487	10-07-2003	Abramovici et al.	

FOREIGN PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages Or Relevant Figures Appear
		Country Code ³ -Number ⁴ -Kind Code ⁵ (if known)			
IJK/	BA	JP-2001-522049	11-13-2001	Credence Systems Corp.	
	BB	JP-2001-506367	05-15-2001	Simd Solutions Inc.	
	BC	JP-2000-267881	09-29-2000	Advantest Corp.	
	BD	JP-2002-141414	05-17-2002	Koninkl Philips Electronics NV	
↓	BE	JP-2001-320386	11-16-2001	Nippon Electric Co.	
	BF	JP-2000-163456	06-16-2000	Hitachi Ltd.	

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 608. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. *CITE NO.: Those application(s) which are marked with an single asterisk (*) next to the Cite No. are not supplied (under 37 CFR 1.98(a)(2)(iii)) because that application was filed after June 30, 2003 or is available in the IFW. ¹ Applicant's unique citation designation number (optional). ² See Kind Codes of USPTO Patent Documents at www.uspto.gov or MPEP 901.04. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. ⁶ Applicant is to place a check mark here if English language Translation is attached.

NON PATENT LITERATURE DOCUMENTS					
Examiner Initials	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.			T ²
IJK/	CA	Explanation of Circumstances Relating To Accelerated Examination submitted in Japanese Application No. 2004-380598 dated March 1, 2007 and English translation thereof, 8 pages			
	CB	European Search Report issued in European Application No. EP 06 07 7162 dated February 23, 2007, 6 pages			
	CC	Xia J. Q. et al.: "Dynamic Test Emulation for EDA-Based Mixed-Signal Test Development Automation" Proceedings of The International Test Conference (ITC). Washington, Octo. 21-25, 1995, New York, IEEE, US, 761-770, XP000552879 ISBN: 0-7803-2992-9			
	CD	Castelnovo A. et al.: "Emulation-Based Design Errors Identification" Defect and Fault Tolerance in VLSI Systems, 2002. DFT 2002. Proceedings. 17th IEEE International Symposium on 6-8 Nov. 2002, Piscataway, NJ, USA, IEEE, 6 November 2002 (2002-11-06), pages 365-371, XP010625026 ISBN: 0-7695-1831-1			
	CE	Japanese Office Action "Notification of Reasons for Rejection" issued in Japanese Application No. 2004-380598 mailed on April 3, 2007 and English translation thereof, 7 pages			
↓	CF	Dearborn, W. R., Perkins, E. G., Wong, J. J., Rolince, D., "The Virtual Test Program (V Test)", 1998 IEEE Autotestcon Proceedings, IEEE Systems Readiness Technology Conference, 1998			
Examiner Signature	/James Kerveros/			Date Considered	08/01/2007

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/JK/		IEEE, U.S.A. IEEE, August 27, 1998, Catalog No. 98CH36179, pages 149-159	
/JK/	CG	U.S. Office Action issued in U.S. Application No. 10/404,002 mailed on April 9, 2007, 16 pages	

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Examiner Signature	/James Kerveros/	Date Considered	08/01/2007
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